

**Search Notes**

Application/Control No.

10/618,365

Examiner

Syed Zaidi

Applicant(s)/Patent under  
Reexamination

NAKAMICHI ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	237	11/16/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	11/16/2007	SZ
Inventors : Nakamichi et al.,	11/16/2007	SZ
(IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	11/16/2007	SZ
(370/237 370/235 370/229 370/235).CCLS.	11/16/2007	SZ
Consulted with SPE Kwang bin Yao.	11/16/2007	SZ